

## **30V N-CHANNEL ENHANCEMENT MODE MOSFET**

#### SUMMARY

 $V_{(BR)DSS}$ =30V;  $R_{DS(ON)}$ =0.045 $\Omega$ ;  $I_{D}$ =5.0A

### DESCRIPTION

This new generation of high density MOSFETs from Zetex utilizes a unique structure that combines the benefits of low on-resistance with fast switching speed. This makes them ideal for high efficiency, low voltage, power management applications.

#### FEATURES

- Low on-resistance
- · Fast switching speed
- · Low threshold
- Low gate drive
- Low profile SOIC package

#### **APPLICATIONS**

- DC DC converters
- Power management functions
- Disconnect switches
- Motor control

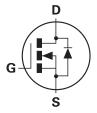
#### **ORDERING INFORMATION**

DEVICE	REEL SIZE (inches)	TAPE WIDTH (mm)	QUANTITY PER REEL
ZXM64N03XTA	7	12 embossed	1,000
ZXM64N03XTC	13	12 embossed	4,000

### **DEVICE MARKING**

ZXM4P03







 S
 ①

 S
 D

 G
 D

Top view



### **ABSOLUTE MAXIMUM RATINGS**

PARAMETER	SYMBOL	LIMIT	UNIT
Drain-Source Voltage	V <sub>DSS</sub>	30	V
Gate- Source Voltage	V <sub>GS</sub>	±20	V
Continuous Drain Current $(V_{GS}=4.5V; T_A=25^{\circ}C)(b) \ (V_{GS}=4.5V; T_A=70^{\circ}C)(b)$	I <sub>D</sub>	5.0 4.0	А
Pulsed Drain Current (c)	I <sub>DM</sub>	30	А
Continuous Source Current (Body Diode)(b)	I <sub>S</sub>	2.4	А
Pulsed Source Current (Body Diode)(c)	I <sub>SM</sub>	30	А
Power Dissipation at T <sub>A</sub> =25°C (a) Linear Derating Factor	P <sub>D</sub>	1.1 8.8	W mW/°C
Power Dissipation at T <sub>A</sub> =25°C (b) Linear Derating Factor	P <sub>D</sub>	1.8 14.4	W mW/°C
Operating and Storage Temperature Range	T <sub>j</sub> :T <sub>stg</sub>	-55 to +150	°C

### THERMAL RESISTANCE

PARAMETER	SYMBOL	VALUE	UNIT
Junction to Ambient (a)	$R_{\theta JA}$	113	°C/W
Junction to Ambient (b)	$R_{ heta JA}$	70	°C/W

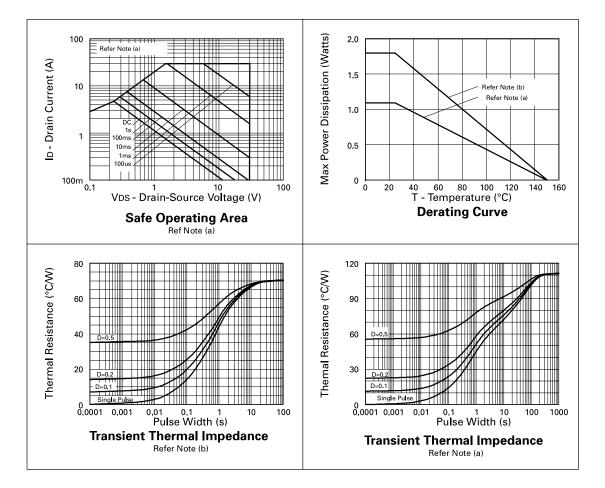
NOTES:

(a) For a device surface mounted on 25mm x 25mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions

(b) For a device surface mounted on FR4 PCB measured at t  ${\leqslant}10$  secs.

(c) Repetitive rating - pulse width limited by maximum junction temperature. Refer to Transient Thermal Impedance graph.





### CHARACTERISTICS



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PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT	CONDITIONS	
STATIC					1		
Drain-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	30			V	I <sub>D</sub> =-250μA, V <sub>GS</sub> =0V	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>			1	μA	V <sub>DS</sub> =30V, V <sub>GS</sub> =0V	
Gate-Body Leakage	I <sub>GSS</sub>			±100	nA	$V_{GS}=\pm 20V, V_{DS}=0V$	
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	1.0			V	$I_{D}^{=-250 \mu A}, V_{DS}^{=} V_{GS}$	
Static Drain-Source On-State Resistance (1)	R <sub>DS(on)</sub>			0.045 0.060	Ω Ω	V <sub>GS</sub> =10V, I <sub>D</sub> =3.7A V <sub>GS</sub> =4.5V, I <sub>D</sub> =1.9A	
Forward Transconductance (3)	g <sub>fs</sub>	4.3			S	V <sub>DS</sub> =10V,I <sub>D</sub> =-1.9A	
DYNAMIC (3)	•					•	
Input Capacitance	Ciss		950		pF		
Output Capacitance	Coss		200		pF	V <sub>DS</sub> =25 V, V <sub>GS</sub> =0V, f=1MHz	
Reverse Transfer Capacitance	C <sub>rss</sub>		50		pF		
SWITCHING(2) (3)							
Turn-On Delay Time	t <sub>d(on)</sub>		4.2		ns		
Rise Time	t <sub>r</sub>		4.5		ns	V <sub>DD</sub> =5V, I <sub>D</sub> =3.7A	
Turn-Off Delay Time	t <sub>d(off)</sub>		20.5		ns	$R_{g}=6.2\Omega$ , $R_{D}=4.0\Omega$ (Refer to test circuit)	
Fall Time	t <sub>f</sub>		8		ns		
Total Gate Charge	Qg			27	nC		
Gate-Source Charge	Q <sub>gs</sub>			5	nC	V <sub>DS</sub> =24V,V <sub>GS</sub> =10V, I <sub>D</sub> =3.7A	
Gate Drain Charge	Q <sub>gd</sub>			4.5	nC	(Refer to test circuit)	
SOURCE-DRAIN DIODE							
Diode Forward Voltage (1)	V <sub>SD</sub>			0.95	V	T <sub>j</sub> =25°C, I <sub>S</sub> =3.7A, V <sub>GS</sub> =0V	
Reverse Recovery Time (3)	t <sub>rr</sub>		24.5		ns	T <sub>j</sub> =25°C, I <sub>F</sub> =3.7A, di/dt= 100A/μs	
Reverse Recovery Charge(3)	Q <sub>rr</sub>		19.1		nC		

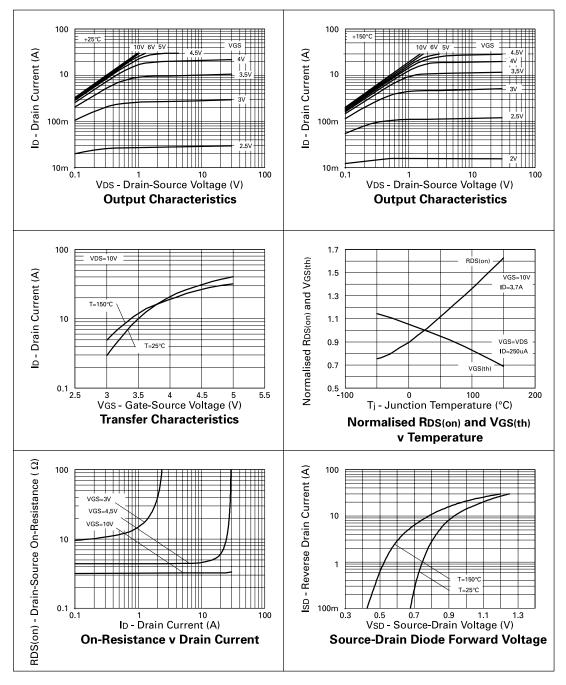
## ELECTRICAL CHARACTERISTICS (at T<sub>amb</sub> = 25°C unless otherwise stated)

(1) Measured under pulsed conditions. Width=300 $\mu s.$  Duty cycle  ${\leq}2\%.$ 

(2) Switching characteristics are independent of operating junction temperature.

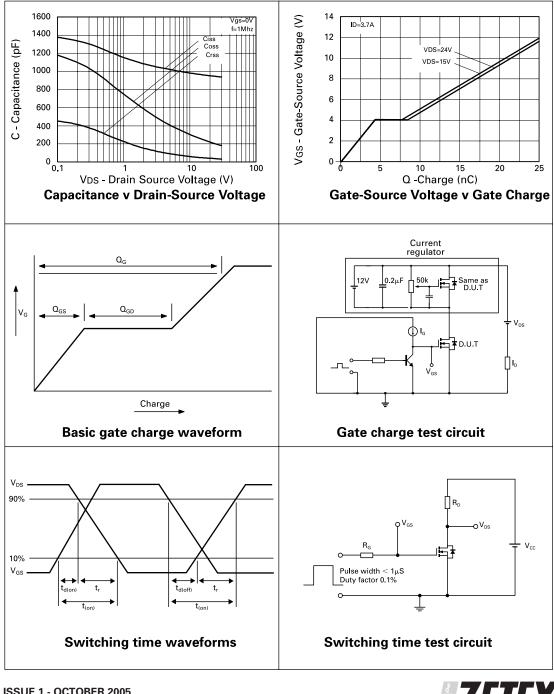
(3) For design aid only, not subject to production testing.





### **TYPICAL CHARACTERISTICS**

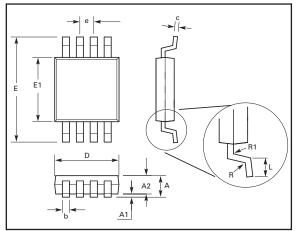


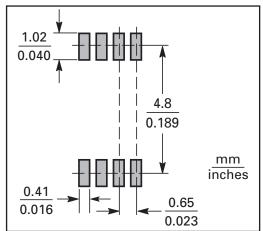


### **TYPICAL CHARACTERISTICS**



### **PACKAGE DETAILS**





PAD LAYOUT DETAILS

### PACKAGE DIMENSIONS

DIM	Millimeters		Inches		
	MIN	МАХ	MIN	МАХ	
А	0.91	1.11	0.036	0.044	
A1	0.10	0.20	0.004	0.008	
В	0.25	0.36	0.010	0.014	
С	0.13	0.18	0.005	0.007	
D	2.95	3.05	0.116	0.120	
е	0.65NOM		0.0256		
e1	0.33	NOM	0.0128		
E	2.95	3.05	0.116	0.120	
Н	4.78	5.03	0.188	0.198	
L	0.41	0.66	0.016	0.026	
θ°	0°	6°	0°	6°	

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